

NO IMAGE



Critical Dimension Flared re-entrant tip

The CDF130C is specially designed for roughness measurements on sidewalls.

Each of its 3 spikes has a very small apex.

To improve wear characteristics these probe are coated with carbon.

Tip Apex Specifications

Tip width	105 - 130 nm
Overhang	13 - 25 nm
Effective Length	300 - 400 nm

Each probe is individually quality inspected by imaging in a SEM. A certificate with measurement values and images will be provided (a sample can be found in the document section).

CDF probes are shipped in packs of 5 tips.

Probe tip, cantilever, and holder chip consist of single crystal silicon.

Each chip is uniquely numbered.

All cantilevers are shipped with Al-reflex coating.

Each probe is individually quality inspected by imaging in a SEM.
A certificate with measurement values and images will be provided (a sample can be found in the document section).

General Specifications

Cantilever dimensions	length = 125 (\pm 15) μ m width = 35 (\pm 3) μ m
Typical stiffness:	40 N/m
Resonant frequency:	300 (\pm 95) kHz
Holder chip dimensions	length = 3.40 mm width = 1.55 mm thickness = 0.32 mm

CDR-SEM: with SEM, no SEM